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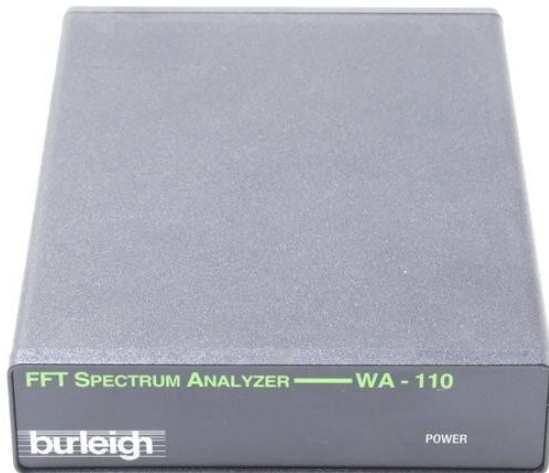
Data Sheet

August 14, 2026

BURLEIGH

Burleigh WA-110 FFT Laser Spectrum Analyzer

Burleigh WA-110 FFT Laser Spectrum Analyzer, Offers detailed laser spectral analysis using fast Fourier transform technology. Measures linewidth and frequency stability, aiding in laser development and quality assurance. Features a clear display and advanced processing.



MODEL

Burleigh WA-110

CALIBRATION

Available on request

CONDITION

Used

STATUS

In stock

RFQ / SKU

WA-110

LISTING

<https://aumictechlabs.com/products/wa-110-2/>

NIST-traceable cal

SAM registered

30-day returns

NAICS 423690 · 811210 · 541380

This unit

The Burleigh WA-1100 Wavemeter delivers precise wavelength measurement for continuous wave (CW) laser sources using a scanning Michelson interferometer architecture. The instrument counts interference fringes from both the input laser and an internal multi-mode HeNe reference laser, deriving wavelength from the fringe count ratio. This approach eliminates the need for external wavelength standards while maintaining absolute accuracy of ± 500 MHz or ± 1 ppm. Automatic air refractive index correction via integrated temperature and pressure sensors ensures measurement validity across environmental conditions. Results display in nm, cm^{-1} , or GHz. The microprocessor-based design supports measurement averaging up to 128 acquisitions and includes a monitor port for direct access to fringe and timing signals. Technical Specifications

Measurement Method: Scanning Michelson interferometer with fringe counting Reference Laser: Multi-mode HeNe, ± 500 MHz or ± 1 ppm absolute accuracy Output Units: nm, cm^{-1} , GHz

Measurement Averaging: Up to 128 measurements Environmental Correction: Automatic air refractive index compensation via temperature and pressure sensors Power Input: 90–260 VAC,

50/60 Hz Key Features Fringe counting eliminates external calibration requirements Automatic environmental correction for field deployment Remote control via RS-232 or GPIB (IEEE-488) SCPI protocol support for integrated instrument control Bi-directional serial communication Monitor port for signal diagnostics Typical Applications CW laser wavelength verification and documentation Reference laser calibration and traceability Tunable laser characterization across tuning ranges Spectroscopy and metrology workflows requiring traceable measurements Compatibility & Integration RS-232 and GPIB interfaces enable integration into automated test systems. SCPI command set supports standard instrument programming across heterogeneous benchtop and ATE environments. Monitor port provides oscilloscope-compatible fringe and timing signals for system diagnostics.

Features & description

From manufacturer datasheet

Built-in HeNe wavelength standard

GPIB and RS-232 control Technical Specifications Model: WA-1100 Instrument Type: Optical wavelength meter Wavelength Range: 700 nm to 1650 nm Frequency Range: 181 THz to 428 THz Wavelength Uncertainty: plus or minus 1 ppm (plus or minus 1.5 pm at 1500 nm) Display Resolution Wavelength: 0.001 nm Wavelength Units: nm vacuum, GHz Power Uncertainty: plus or minus 0.5 dB at plus or minus 30 nm from 1310 nm and 1550 nm Power Resolution: plus or minus 0.05 dB Power Linearity: plus or minus 0.3 dB Power Display Resolution: 0.01 dB Power Units: dBm, mW, uW Sensitivity 1200 to 1600 nm: -30 dBm (1 uW) Sensitivity 700 to 1650 nm Typical: -20 dBm (10 uW) Maximum Input Level: 10 dBm (10 mW) Maximum Safe Level: 18 dBm (63 mW) Measurement Update Time: 0.1 s (10 measurements/s) Optical Input Fiber: 9/125 um Connector Options: FC/UPC FC/APC SC/UPC SC/APC ST/UPC Instrument Interfaces: GPIB IEEE-488.2, RS-232, LabVIEW, LabWindows Operating Temperature: 15 C to 30 C Storage Temperature: -10 C to 70 C Pressure Range: 500 to 900 mm Hg Relative Humidity: less than or equal to 90 percent RH at 30 C no condensation Dimensions HxWxD: 89 mm x 431.8 mm x 419.1 mm Weight: 7.5 kg Power Requirements: 90 to 260 VAC 50/60 Hz

WA110 Characteristics / Specifications

PARAMETER	VALUE
Model	WA-1100
Instrument Type	Optical wavelength meter
Wavelength Range	700 nm to 1650 nm
Frequency Range	181 THz to 428 THz
Wavelength Uncertainty	plus or minus 1 ppm (plus or minus 1.5 pm at 1500 nm)
Display Resolution Wavelength	0.001 nm
Wavelength Units	nm vacuum, GHz
Power Uncertainty	plus or minus 0.5 dB at plus or minus 30 nm from 1310 nm and 1550 nm
Power Resolution	plus or minus 0.05 dB
Power Linearity	plus or minus 0.3 dB
Power Display Resolution	0.01 dB
Power Units	dBm, mW, uW
Sensitivity 1200 to 1600 nm	-30 dBm (1 uW)
Sensitivity 700 to 1650 nm Typical	-20 dBm (10 uW)
Maximum Input Level	10 dBm (10 mW)
Maximum Safe Level	18 dBm (63 mW)
Measurement Update Time	0.1 s (10 measurements/s)
Optical Input Fiber	9/125 um
Connector Options	FC/UPC FC/APC SC/UPC SC/APC ST/UPC
Instrument Interfaces	GPIB IEEE-488.2, RS-232, LabVIEW, LabWindows
Operating Temperature	15 C to 30 C
Storage Temperature	-10 C to 70 C
Pressure Range	500 to 900 mm Hg
Relative Humidity	less than or equal to 90 percent RH at 30 C no condensation
Dimensions HxWxD	89 mm x 431.8 mm x 419.1 mm

PARAMETER	VALUE
Weight	7.5 kg
Power Requirements	90 to 260 VAC 50/60 Hz
Linewidth Condition	for linewidths less than 10 GHz
Linewidth	Condition: for linewidths less than 10 GHz
Humidity	less than or equal to 90 percent RH at 30 C no condensation

General Specifications & Supplementary Characteristics

PARAMETER	VALUE
Storage temperature	10 C to 70 C
Operating temperature	15 C to 30 C
Operating Temperature	15 C to 30 C
Humidity	less than or equal to 90 percent RH at 30 C no condensation
Pressure Range	500 to 900 mm Hg
Relative Humidity	less than or equal to 90 percent RH at 30 C no condensation
Dimensions HxWxD	89 mm x 431.8 mm x 419.1 mm
Weight	7.5 kg
Power Requirements	90 to 260 VAC 50/60 Hz
Linewidth Condition	for linewidths less than 10 GHz Notes From EXFO/Burleigh WA-1650/1150/1100 Wavemeter Optical Wavelength Meters specification sheet SPWA1650/1150/1100.4AN columns for WA-1100. CW measurements; wavelength uncertainty note applies for wavelengths above 1200 nm on that sheet.

Full OEM specifications

Complete technical content extracted from the manufacturer datasheet. Sparse OEM tables are reconstructed as tables below; other text is preserved as paragraphs.

Specifications	
Specifications	
PARAMETER	VALUE
Model	WA-1100
Instrument Type	Optical wavelength meter
Wavelength Range	700 nm to 1650 nm
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Wavelength Uncertainty	plus or minus 1 ppm (plus or minus 1.5 pm at 1500 nm)
Display Resolution Wavelength	0.001 nm
Wavelength Units	nm vacuum, GHz
Power Uncertainty	plus or minus 0.5 dB at plus or minus 30 nm from 1310 nm and 1550 nm
Power Resolution	plus or minus 0.05 dB
Power Linearity	plus or minus 0.3 dB
Power Display Resolution	0.01 dB
Power Units	dBm, mW, uW
Sensitivity 1200 to 1600 nm	-30 dBm (1 uW)
Sensitivity 700 to 1650 nm Typical	-20 dBm (10 uW)
Maximum Input Level	10 dBm (10 mW)
Maximum Safe Level	18 dBm (63 mW)
Measurement Update Time	0.1 s (10 measurements/s)
Optical Input Fiber	9/125 um
Connector Options	FC/UPC FC/APC SC/UPC SC/APC ST/UPC
Instrument Interfaces	GPiB IEEE-488.2, RS-232, LabVIEW, LabWindows
Operating Temperature	15 C to 30 C
Storage Temperature	-10 C to 70 C
Pressure Range	500 to 900 mm Hg
Relative Humidity	less than or equal to 90 percent RH at 30 C no condensation
Dimensions HxWxD	89 mm x 431.8 mm x 419.1 mm
Weight	7.5 kg

PARAMETER	VALUE
Power Requirements	90 to 260 VAC 50/60 Hz
Linewidth Condition	for linewidths less than 10 GHz

Notes

From EXFO/Burleigh WA-1650/1150/1100 Wavemeter Optical Wavelength Meters specification sheet
SPWA1650/1150/1100.4AN columns for WA-1100. CW measurements; wavelength uncertainty note applies for
wavelengths above 1200 nm on that sheet.

Available from Aumictech

Used and refurbished unit evaluated in-house. Calibration: Available on request. Used · In stock.

Request a quote: sales@aumictech.com · +1 (484) 841-9341

Aumictech

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NIST-traceable calibration · SAM registered ·
30-day returns
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Technical content from manufacturer specifications. Unit photo/stock from Aumictech listing when available. Specifications subject to OEM documentation and unit condition.